

| L Number | Hits  | Search Text   | DB                                 | Time stamp       |
|----------|-------|---|------------------------------------|------------------|
| 1        | 31363 | semiconductor and sample and stage  | USPAT; US-PGPUB; EPO; JPO; IBM_TDB | 2004/10/28 11:15 |
| 2        | 7813  | (semiconductor and sample and stage) and defect   | USPAT; US-PGPUB; EPO; JPO; IBM_TDB | 2004/10/28 11:15 |
| 3        | 640   | ((semiconductor and sample and stage) and defect) and (secondary adj (electron or particle))  | USPAT; US-PGPUB; EPO; JPO; IBM_TDB | 2004/10/28 11:16 |
| 4        | 347   | ((((semiconductor and sample and stage) and defect) and (secondary adj (electron or particle))) and target  | USPAT; US-PGPUB; EPO; JPO; IBM_TDB | 2004/10/28 11:17 |
| 5        | 95    | ((((semiconductor and sample and stage) and defect) and (secondary adj (electron or particle))) and target) and (position near4 defect)   | USPAT; US-PGPUB; EPO; JPO; IBM_TDB | 2004/10/28 11:17 |
| 6        | 95    | (((((semiconductor and sample and stage) and defect) and (secondary adj (electron or particle))) and target) and (position near4 defect)) and image   | USPAT; US-PGPUB; EPO; JPO; IBM_TDB | 2004/10/28 11:18 |
| 7        | 73    | ((((((semiconductor and sample and stage) and defect) and (secondary adj (electron or particle))) and target) and (position near4 defect)) and image) and irradiation   | USPAT; US-PGPUB; EPO; JPO; IBM_TDB | 2004/10/28 11:18 |
| 8        | 59    | (((((((semiconductor and sample and stage) and defect) and (secondary adj (electron or particle))) and target) and (position near4 defect)) and image) and irradiation) and resolution  | USPAT; US-PGPUB; EPO; JPO; IBM_TDB | 2004/10/28 11:19 |
| 9        | 56    | (((((((semiconductor and sample and stage) and defect) and (secondary adj (electron or particle))) and target) and (position near4 defect)) and image) and irradiation) and resolution) and (emitted or emission)   | USPAT; US-PGPUB; EPO; JPO; IBM_TDB | 2004/10/28 11:20 |
| 10       | 1     | ((((((((semiconductor and sample and stage) and defect) and (secondary adj (electron or particle))) and target) and (position near4 defect)) and image) and irradiation) and resolution) and (emitted or emission)) and (first adj resolution)  | USPAT; US-PGPUB; EPO; JPO; IBM_TDB | 2004/10/28 11:21 |
| 11       | 53    | ((((((((semiconductor and sample and stage) and defect) and (secondary adj (electron or particle))) and target) and (position near4 defect)) and image) and irradiation) and resolution) and (emitted or emission)) and magnification   | USPAT; US-PGPUB; EPO; JPO; IBM_TDB | 2004/10/28 11:22 |
| 12       | 23    | (((((((((semiconductor and sample and stage) and defect) and (secondary adj (electron or particle))) and target) and (position near4 defect)) and image) and irradiation) and resolution) and (emitted or emission)) and magnification) and (magnification adj image)                           | USPAT; US-PGPUB; EPO; JPO; IBM_TDB | 2004/10/28 11:43 |
| 13       | 1     | (((((((((semiconductor and sample and stage) and defect) and (secondary adj (electron or particle))) and target) and (position near4 defect)) and image) and irradiation) and resolution) and (emitted or emission)) and magnification) and (magnification adj image)) and (plural adj defects) | USPAT; US-PGPUB; EPO; JPO; IBM_TDB | 2004/10/28 11:39 |